EFM8 Sleepy Bee Family
EFM8SB2 Data Sheet

The EFM8SB2, part of the Sleepy Bee family of MCUs, is the world's most energy friendly 8-bit microcontrollers with a comprehensive feature set in small packages.
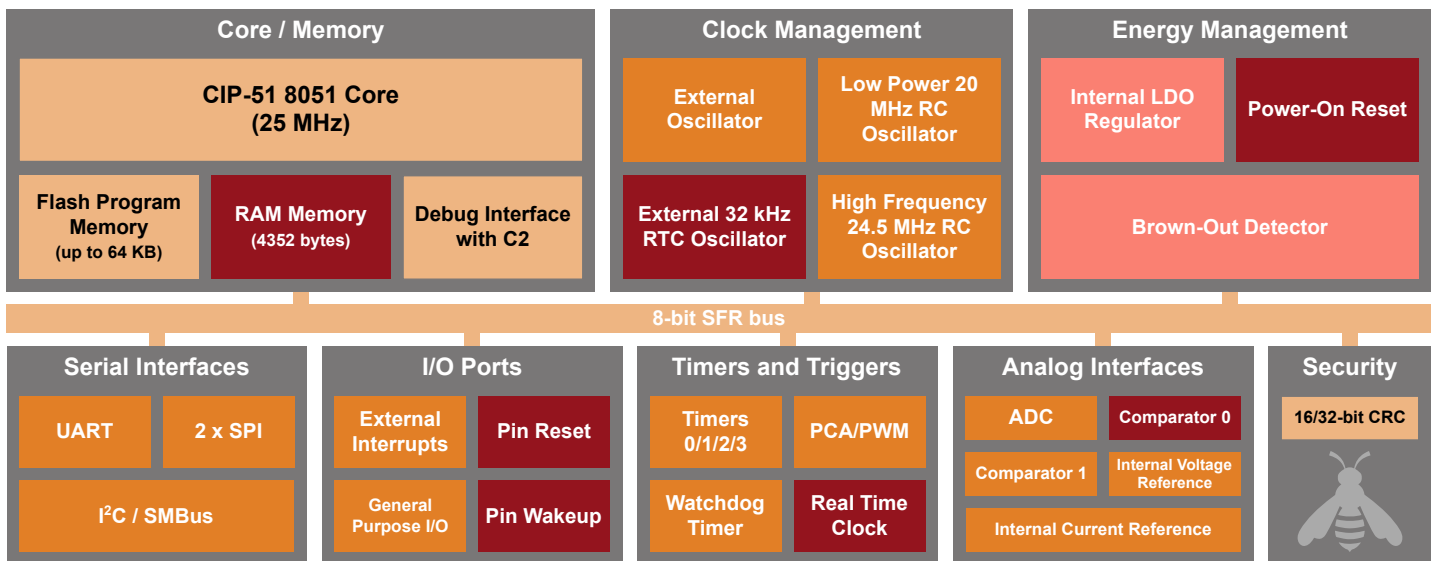
These devices offer lowest power consumption by combining innovative low energy techniques and short wakeup times from energy saving modes into small packages, making them well-suited for any battery operated applications. With an efficient 8051 core, 6-bit current reference, and precision analog, the EFM8SB2 family is also optimal for embedded applications.

EFM8SB2 applications include the following:

- Hand-held devices
- Industrial controls
- Battery-operated consumer electronics
- Sensor interfaces

ENERGY FRIENDLY FEATURES

- Lowest MCU sleep current with supply brownout detection (50 nA)
- Lowest MCU active current with these features (170 µA / MHz at 24.5 MHz clock rate)
- Lowest MCU sleep current using internal RTC operating and supply brownout detection (<300 nA)
- Ultra-fast wake up for digital and analog peripherals (< 2 µs)
- Integrated low drop out (LDO) voltage regulator to maintain ultra-low active current at all voltages

Core / Memory

CIP-51 8051 Core (25 MHz)

Flash Program Memory (up to 64 KB) | **RAM Memory (4352 bytes)** | **Debug Interface with C2**

Clock Management

External Oscillator | **Low Power 20 MHz RC Oscillator**

External 32 kHz RTC Oscillator | **High Frequency 24.5 MHz RC Oscillator**

Energy Management

Internal LDO Regulator | **Power-On Reset**

Brown-Out Detector

8-bit SFR bus

Serial Interfaces

UART | **2 x SPI**

I²C / SMBus

I/O Ports

External Interrupts | **Pin Reset**

General Purpose I/O | **Pin Wakeup**

Timers and Triggers

Timers 0/1/2/3 | **PCA/PWM**

Watchdog Timer | **Real Time Clock**

Analog Interfaces

ADC | **Comparator 0**

Comparator 1 | **Internal Voltage Reference**

Internal Current Reference

Security

16/32-bit CRC

Lowest power mode with peripheral operational:

■ Normal ■ Idle ■ Suspend ■ Sleep

1. Feature List

The EFM8SB2 highlighted features are listed below.

- Core:
    - Pipelined CIP-51 Core
    - Fully compatible with standard 8051 instruction set
    - 70% of instructions execute in 1-2 clock cycles
    - 25 MHz maximum operating frequency
- Memory:
    - Up to 64 kB flash memory, in-system re-programmable from firmware.
    - Up to 4352 bytes RAM (including 256 bytes standard 8051 RAM and 4096 bytes on-chip XRAM)
- Power:
    - Internal LDO regulator for CPU core voltage
    - Power-on reset circuit and brownout detectors
- I/O: Up to 24 total multifunction I/O pins:
    - Flexible peripheral crossbar for peripheral routing
    - 5 mA source, 12.5 mA sink allows direct drive of LEDs
- Clock Sources:
    - Internal 20 MHz low power oscillator with ±10% accuracy
    - Internal 24.5 MHz precision oscillator with ±2% accuracy
    - External RTC 32 kHz crystal
    - External crystal, RC, C, and CMOS clock options

- Timers/Counters and PWM:
    - 32-bit Real Time Clock (RTC)
    - 6-channel programmable counter array (PCA) supporting PWM, capture/compare, and frequency output modes with watchdog timer function
    - 4 x 16-bit general-purpose timers
- Communications and Digital Peripherals:
    - UART
    - 2 x SPI™ Master / Slave
    - SMBus™/I2C™ Master / Slave
    - External Memory Interface (EMIF)
    - 16-bit/32-bit CRC unit, supporting automatic CRC of flash at 1024-byte boundaries
- Analog:
    - Programmable current reference (IREF0)
    - 10-Bit Analog-to-Digital Converter (ADC0)
    - 2 x Low-current analog comparators
- On-Chip, Non-Intrusive Debugging
    - Full memory and register inspection
    - Four hardware breakpoints, single-stepping
- Pre-loaded UART bootloader
- Temperature range -40 to 85 ºC
- Single power supply 1.8 to 3.6 V
- QFP32, QFN32, and QFN24 packages

With on-chip power-on reset, voltage supply monitor, watchdog timer, and clock oscillator, the EFM8SB2 devices are truly standalone system-on-a-chip solutions. The flash memory is reprogrammable in-circuit, providing non-volatile data storage and allowing field up-grades of the firmware. The on-chip debugging interface (C2) allows non-intrusive (uses no on-chip resources), full speed, in-circuit debugging using the production MCU installed in the final application. This debug logic supports inspection and modification of memory and registers, setting breakpoints, single stepping, and run and halt commands. All analog and digital peripherals are fully functional while debugging. Each device is specified for 1.8 to 3.6 V operation and is available in 24-pin QFN, 32-pin QFN, or 32-pin QFP packages. All package options are lead-free and RoHS compliant.
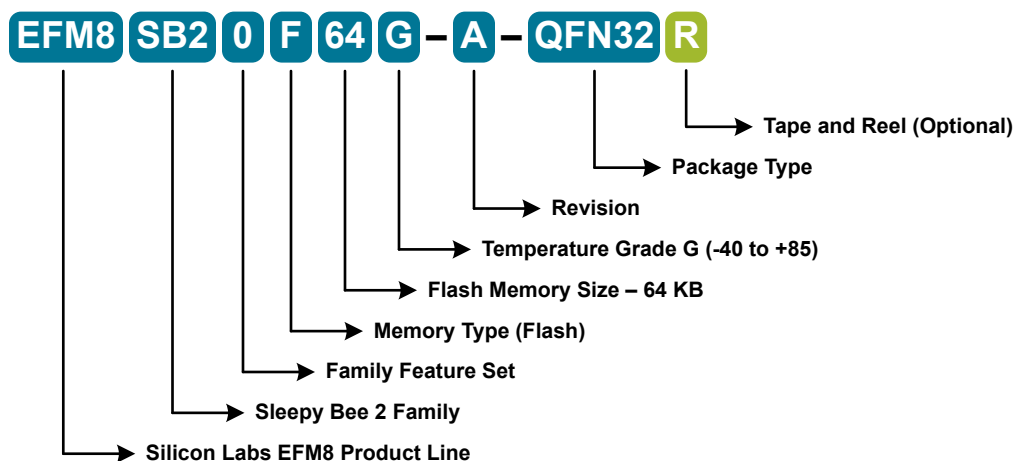
2. Ordering Information

Figure 2.1. EFM8SB2 Part Numbering

All EFM8SB2 family members have the following features:

- CIP-51 Core running up to 25 MHz
- Three Internal Oscillators (24.5 MHz, 20 MHz, and 16 kHz)
- SMBus / I2C
- 2 x SPI
- UART
- 6-Channel Programmable Counter Array (PWM, Clock Generation, Capture/Compare)
- 4 16-bit Timers
- 2 Analog Comparators
- 6-bit programmable current reference
- 10-bit Analog-to-Digital Converter with integrated multiplexer, voltage reference, and temperature sensor
- Low-current 32 kHz oscillator and Real Time Clock
- 16-bit CRC Unit
- Pre-loaded UART bootloader

In addition to these features, each part number in the EFM8SB2 family has a set of features that vary across the product line. The product selection guide shows the features available on each family member.

Table 2.1. Product Selection Guide

Ordering Part Number	Flash Memory (kB)	RAM (Bytes)	Digital Port I/Os (Total)	ADC Channels	Comparator Inputs	Pb-free (RoHS Compliant)	Temperature Range	Package
EFM8SB20F64G-A-QFN32	64	4352	24	23	12	Yes	-40 to +85 C	QFN32
EFM8SB20F64G-A-QFP32	64	4352	24	23	12	Yes	-40 to +85 C	QFP32
EFM8SB20F64G-A-QFN24	64	4352	16	15	8	Yes	-40 to +85 C	QFN24
EFM8SB20F32G-A-QFN32	32	4352	24	23	12	Yes	-40 to +85 C	QFN32
EFM8SB20F32G-A-QFP32	32	4352	24	23	12	Yes	-40 to +85 C	QFP32
EFM8SB20F32G-A-QFN24	32	4352	16	15	8	Yes	-40 to +85 C	QFN24

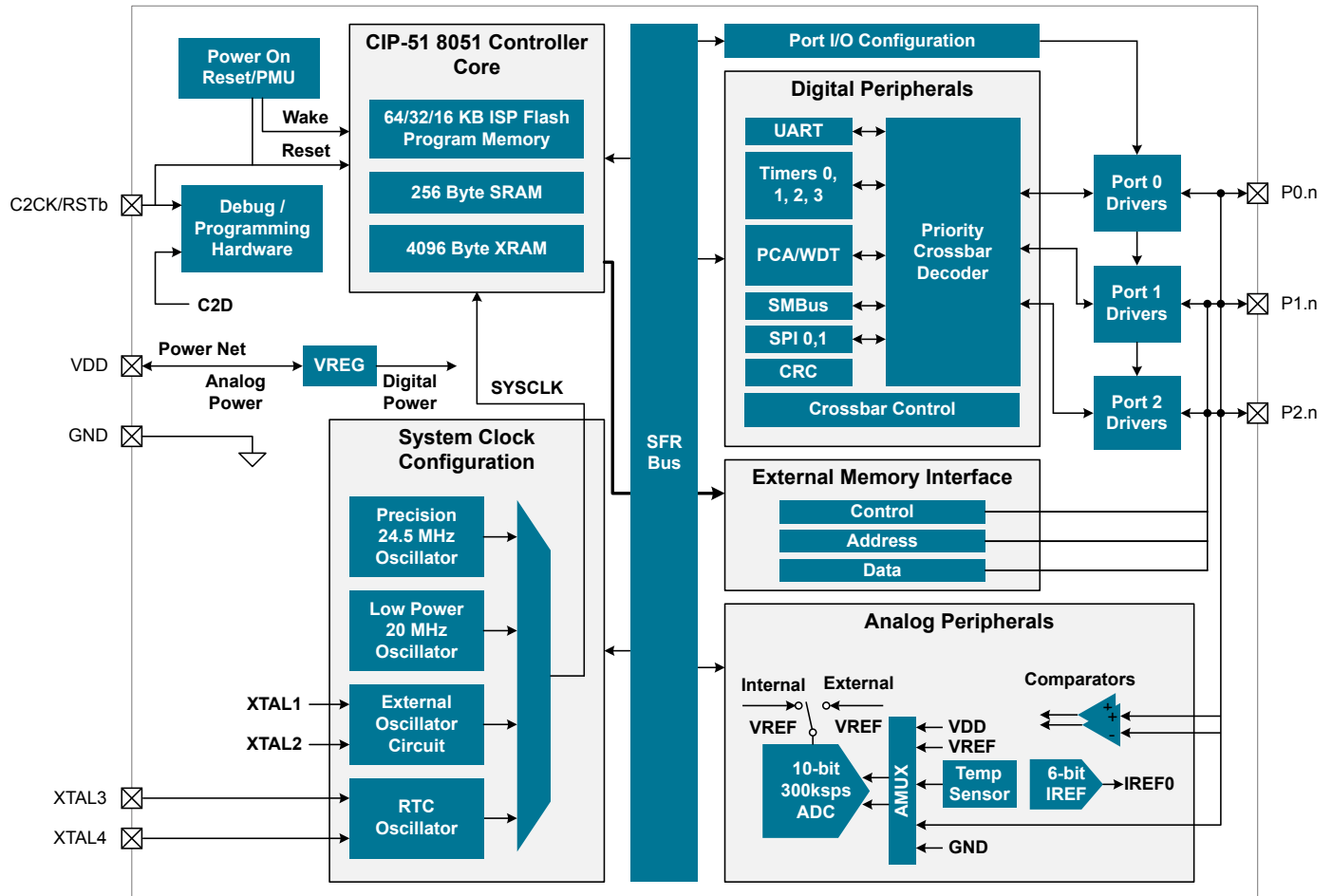| Ordering Part Number	Flash Memory (kB)	RAM (Bytes)	Digital Port I/Os (Total)	ADC Channels	Comparator Inputs	Pb-free (RoHS Compliant)	Temperature Range	Package
EFM8SB20F16G-A-QFN24	16	4352	16	15	8	Yes	-40 to +85 C	QFN24

3. System Overview

3.1 Introduction

Figure 3.1. Detailed EFM8SB2 Block Diagram

3.2 Power

All internal circuitry draws power from the VDD supply pin. External I/O pins are powered from the VIO supply voltage (or VDD on devices without a separate VIO connection), while most of the internal circuitry is supplied by an on-chip LDO regulator. Control over the device power can be achieved by enabling/disabling individual peripherals as needed. Each analog peripheral can be disabled when not in use and placed in low power mode. Digital peripherals, such as timers and serial buses, have their clocks gated off and draw little power when they are not in use.

Table 3.1. Power Modes

Power Mode	Details	Mode Entry	Wake-Up Sources
Normal	Core and all peripherals clocked and fully operational	—	—
Idle	• Core halted • All peripherals clocked and fully operational • Code resumes execution on wake event	Set IDLE bit in PCON0	Any interrupt
Suspend	• Core and digital peripherals halted • Internal oscillators disabled • Code resumes execution on wake event	1. Switch SYSCLK to HFOSC0 or LPOSC0 2. Set SUSPEND bit in PMU0CF	• RTC0 Alarm Event • RTC0 Fail Event • Port Match Event • Comparator 0 Rising Edge
Sleep	• Most internal power nets shut down • Select circuits remain powered • Pins retain state • All RAM and SFRs retain state • Code resumes execution on wake event	1. Disable unused analog peripherals 2. Set SLEEP bit in PMU0CF	• RTC0 Alarm Event • RTC0 Fail Event • Port Match Event • Comparator 0 Rising Edge

3.3 I/O

Digital and analog resources are externally available on the device's multi-purpose I/O pins. Port pins P0.0-P2.6 can be defined as general-purpose I/O (GPIO), assigned to one of the internal digital resources through the crossbar or dedicated channels, or assigned to an analog function. Port pin P2.7 can be used as GPIO. Additionally, the C2 Interface Data signal (C2D) is shared with P2.7.

• Up to 24 multi-functions I/O pins, supporting digital and analog functions.
• Flexible priority crossbar decoder for digital peripheral assignment.
• Two drive strength settings for each pin.
• Two direct-pin interrupt sources with dedicated interrupt vectors (INT0 and INT1).
• Up to 16 direct-pin interrupt sources with shared interrupt vector (Port Match).

3.4 Clocking

The CPU core and peripheral subsystem may be clocked by both internal and external oscillator resources. By default, the system clock comes up running from the 20 MHz low power oscillator divided by 8.

• Provides clock to core and peripherals.
• 20 MHz low power oscillator (LPOSC0), accurate to +/- 10% over supply and temperature corners.
• 24.5 MHz internal oscillator (HFOSC0), accurate to +/- 2% over supply and temperature corners.
• External RTC 32 kHz crystal.
• External RC, C, CMOS, and high-frequency crystal clock options (EXTCLK).
• Clock divider with eight settings for flexible clock scaling: Divide the selected clock source by 1, 2, 4, 8, 16, 32, 64, or 128.

3.5 Counters/Timers and PWM

Real Time Clock (RTC0)

The RTC is an ultra low power, 36 hour 32-bit independent time-keeping Real Time Clock with alarm. The RTC has a dedicated 32 kHz oscillator. No external resistor or loading capacitors are required, and a missing clock detector features alerts the system if the external crystal fails. The on-chip loading capacitors are programmable to 16 discrete levels allowing compatibility with a wide range of crystals.

The RTC module includes the following features:
- Up to 36 hours (32-bit) of independent time keeping.
- Support for external 32 kHz crystal or internal self-oscillate mode.
- Internal crystal loading capacitors with 16 levels.
- Operation in the lowest power mode and across the full supported voltage range.
- Alarm and oscillator failure events to wake from the lowest power mode or reset the device.

Programmable Counter Array (PCA0)

The programmable counter array (PCA) provides multiple channels of enhanced timer and PWM functionality while requiring less CPU intervention than standard counter/timers. The PCA consists of a dedicated 16-bit counter/timer and one 16-bit capture/compare module for each channel. The counter/timer is driven by a programmable timebase that has flexible external and internal clocking options. Each capture/compare module may be configured to operate independently in one of five modes: Edge-Triggered Capture, Software Timer, High-Speed Output, Frequency Output, or Pulse-Width Modulated (PWM) Output. Each capture/compare module has its own associated I/O line (CEXn) which is routed through the crossbar to port I/O when enabled.

- 16-bit time base.
- Programmable clock divisor and clock source selection.
- Up to six independently-configurable channels
- 8, 9, 10, 11 and 16-bit PWM modes (edge-aligned operation).
- Frequency output mode.
- Capture on rising, falling or any edge.
- Compare function for arbitrary waveform generation.
- Software timer (internal compare) mode.
- Integrated watchdog timer.

Timers (Timer 0, Timer 1, Timer 2, and Timer 3)

Several counter/timers are included in the device: two are 16-bit counter/timers compatible with those found in the standard 8051, and the rest are 16-bit auto-reload timers for timing peripherals or for general purpose use. These timers can be used to measure time intervals, count external events and generate periodic interrupt requests. Timer 0 and Timer 1 are nearly identical and have four primary modes of operation. The other timers offer both 16-bit and split 8-bit timer functionality with auto-reload and capture capabilities.

Timer 0 and Timer 1 include the following features:
- Standard 8051 timers, supporting backwards-compatibility with firmware and hardware.
- Clock sources include SYSCLK, SYSCLK divided by 12, 4, or 48, the External Clock divided by 8, or an external pin.
- 8-bit auto-reload counter/timer mode
- 13-bit counter/timer mode
- 16-bit counter/timer mode
- Dual 8-bit counter/timer mode (Timer 0)

Timer 2 and Timer 3 are 16-bit timers including the following features:
- Clock sources include SYSCLK, SYSCLK divided by 12, or the External Clock divided by 8.
- 16-bit auto-reload timer mode
- Dual 8-bit auto-reload timer mode
- Comparator 0 or RTC0 capture (Timer 2)
- Comparator 1 or EXTCLK/8 capture (Timer 3)

Watchdog Timer (WDT0)

The device includes a programmable watchdog timer (WDT) integrated within the PCA0 peripheral. A WDT overflow forces the MCU into the reset state. To prevent the reset, the WDT must be restarted by application software before overflow. If the system experiences a software or hardware malfunction preventing the software from restarting the WDT, the WDT overflows and causes a reset. Following a reset, the WDT is automatically enabled and running with the default maximum time interval. If needed, the WDT can be disabled by system software. The state of the RSTb pin is unaffected by this reset.

The Watchdog Timer integrated in the PCA0 peripheral has the following features:
- Programmable timeout interval
- Runs from the selected PCA clock source
- Automatically enabled after any system reset

3.6 Communications and Other Digital Peripherals

Universal Asynchronous Receiver/Transmitter (UART0)

UART0 is an asynchronous, full duplex serial port offering modes 1 and 3 of the standard 8051 UART. Enhanced baud rate support allows a wide range of clock sources to generate standard baud rates. Received data buffering allows UART0 to start reception of a second incoming data byte before software has finished reading the previous data byte.

The UART module provides the following features:
- Asynchronous transmissions and receptions
- Baud rates up to SYSCLK/2 (transmit) or SYSCLK/8 (receive)
- 8- or 9-bit data
- Automatic start and stop generation

Serial Peripheral Interface (SPI0 and SPI1)

The serial peripheral interface (SPI) module provides access to a flexible, full-duplex synchronous serial bus. The SPI can operate as a master or slave device in both 3-wire or 4-wire modes, and supports multiple masters and slaves on a single SPI bus. The slave-select (NSS) signal can be configured as an input to select the SPI in slave mode, or to disable master mode operation in a multi-master environment, avoiding contention on the SPI bus when more than one master attempts simultaneous data transfers. NSS can also be configured as a firmware-controlled chip-select output in master mode, or disabled to reduce the number of pins required. Additional general purpose port I/O pins can be used to select multiple slave devices in master mode.

The SPI module includes the following features:
- Supports 3- or 4-wire operation in master or slave modes.
- Supports external clock frequencies up to SYSCLK / 2 in master mode and SYSCLK / 10 in slave mode.
- Support for four clock phase and polarity options.
- 8-bit dedicated clock clock rate generator.
- Support for multiple masters on the same data lines.

System Management Bus / I2C (SMB0)

The SMBus I/O interface is a two-wire, bi-directional serial bus. The SMBus is compliant with the System Management Bus Specification, version 1.1, and compatible with the I^2C serial bus.

The SMBus module includes the following features:
- Standard (up to 100 kbps) and Fast (400 kbps) transfer speeds.
- Support for master, slave, and multi-master modes.
- Hardware synchronization and arbitration for multi-master mode.
- Clock low extending (clock stretching) to interface with faster masters.
- Hardware support for 7-bit slave and general call address recognition.
- Firmware support for 10-bit slave address decoding.
- Ability to inhibit all slave states.
- Programmable data setup/hold times.

External Memory Interface (EMIF0)

The External Memory Interface (EMIF) enables access of off-chip memories and memory-mapped devices connected to the GPIO ports. The external memory space may be accessed using the external move instruction (MOVX) with the target address specified in either 8-bit or 16-bit formats.

- Supports multiplexed memory access.
- Four external memory modes:
  - Internal only.
  - Split mode without bank select.
  - Split mode with bank select.
  - External only
- Configurable ALE (address latch enable) timing.
- Configurable address setup and hold times.
- Configurable write and read pulse widths.

16/32-bit CRC (CRC0)

The cyclic redundancy check (CRC) module performs a CRC using a 16-bit or 32-bit polynomial. CRC0 accepts a stream of 8-bit data and posts the result to an internal register. In addition to using the CRC block for data manipulation, hardware can automatically CRC the flash contents of the device.

The CRC module is designed to provide hardware calculations for flash memory verification and communications protocols. The CRC module includes the following features:
- Support for CCITT-16 polynomial (0x1021).
- Support for CRC-32 polynomial (0x04C11DB7).
- Byte-level bit reversal.
- Automatic CRC of flash contents on one or more 1024-byte blocks.
- Initial seed selection of 0x0000/0x00000000 or 0xFFFF/0xFFFFFFFF.

3.7 Analog

Programmable Current Reference (IREF0)

The programmable current reference (IREF0) module enables current source or sink with two output current settings: Low Power Mode and High Current Mode. The maximum current output in Low Power Mode is 63 μA (1 μA steps) and the maximum current output in High Current Mode is 504 μA (8 μA steps).

The IREF module includes the following features:
- Capable of sourcing or sinking current in programmable steps.
- Two operational modes: Low Power Mode and High Current Mode.

10-Bit Analog-to-Digital Converter (ADC0)

The ADC is a successive-approximation-register (SAR) ADC with 10- and 8-bit modes, integrated track-and hold and a programmable window detector. The ADC is fully configurable under software control via several registers. The ADC may be configured to measure different signals using the analog multiplexer. The voltage reference for the ADC is selectable between internal and external reference sources.

- Up to 22 external inputs.
- Single-ended 10-bit mode.
- Supports an output update rate of 300 ksps samples per second.
- Operation in low power modes at lower conversion speeds.
- Asynchronous hardware conversion trigger, selectable between software, external I/O and internal timer sources.
- Output data window comparator allows automatic range checking.
- Support for burst mode, which produces one set of accumulated data per conversion-start trigger with programmable power-on settling and tracking time.
- Conversion complete and window compare interrupts supported.
- Flexible output data formatting.
- Includes an internal 1.65 V fast-settling reference and support for external reference.
- Integrated temperature sensor.

Low Current Comparators (CMP0, CMP1)

Analog comparators are used to compare the voltage of two analog inputs, with a digital output indicating which input voltage is higher. External input connections to device I/O pins and internal connections are available through separate multiplexers on the positive and negative inputs. Hysteresis, response time, and current consumption may be programmed to suit the specific needs of the application.

The comparator module includes the following features:
- Up to 12 external positive inputs.
- Up to 11 external negative inputs.
- Additional input options:
  - Capacitive Sense Comparator output.
  - VDD.
  - VDD divided by 2.
  - Internal connection to LDO output.
  - Direct connection to GND.
- Synchronous and asynchronous outputs can be routed to pins via crossbar.
- Programmable hysteresis between 0 and +/-20 mV.
- Programmable response time.
- Interrupts generated on rising, falling, or both edges.

3.8 Reset Sources

Reset circuitry allows the controller to be easily placed in a predefined default condition. On entry to this reset state, the following occur:

- The core halts program execution.
- Module registers are initialized to their defined reset values unless the bits reset only with a power-on reset.
- External port pins are forced to a known state.
- Interrupts and timers are disabled.

All registers are reset to the predefined values noted in the register descriptions unless the bits only reset with a power-on reset. The contents of RAM are unaffected during a reset; any previously stored data is preserved as long as power is not lost. The Port I/O latches are reset to 1 in open-drain mode. Weak pullups are enabled during and after the reset. For Supply Monitor and power-on resets, the RSTb pin is driven low until the device exits the reset state. On exit from the reset state, the program counter (PC) is reset, and the system clock defaults to an internal oscillator. The Watchdog Timer is enabled, and program execution begins at location 0x0000.

Reset sources on the device include the following:

- Power-on reset
- External reset pin
- Comparator reset
- Software-triggered reset
- Supply monitor reset (monitors VDD supply)
- Watchdog timer reset
- Missing clock detector reset
- Flash error reset
- RTC0 alarm or oscillator failure

3.9 Debugging

The EFM8SB2 devices include an on-chip Silicon Labs 2-Wire (C2) debug interface to allow flash programming and in-system debugging with the production part installed in the end application. The C2 interface uses a clock signal (C2CK) and a bi-directional C2 data signal (C2D) to transfer information between the device and a host system. See the C2 Interface Specification for details on the C2 protocol.

3.10 Bootloader

All devices come pre-programmed with a UART bootloader. This bootloader resides in flash and can be erased if it is not needed.

4. Electrical Specifications

4.1 Electrical Characteristics

All electrical parameters in all tables are specified under the conditions listed in Table 4.1 Recommended Operating Conditions on page 11, unless stated otherwise.

Table 4.1. Recommended Operating Conditions

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Operating Supply Voltage on VDD	V_{DD}		1.8	2.4	3.6	V
Minimum RAM Data Retention Voltage on VDD[1]	V_{RAM}	Not in Sleep Mode	—	1.4	—	V
		Sleep Mode	—	0.3	0.5	V
System Clock Frequency	f_{SYSCLK}		0	—	25	MHz
Operating Ambient Temperature	T_A		–40	—	85	°C

Note:
1. All voltages with respect to GND.

Table 4.2. Power Consumption

Parameter	Symbol	Conditions	Min	Typ	Max	Units
Digital Supply Current						
Normal Mode supply current - Full speed with code executing from flash [3,4,5]	I_{DD}	V_{DD} = 1.8–3.6 V, f_{SYSCLK} = 24.5 MHz	—	4.1	5.0	mA
		V_{DD} = 1.8–3.6 V, f_{SYSCLK} = 20 MHz	—	3.5	—	mA
		V_{DD} = 1.8–3.6 V, f_{SYSCLK} = 32.768 kHz	—	90	—	µA
Normal Mode supply current frequency sensitivity[1,3,5]	I_{DDFREQ}	V_{DD} = 1.8–3.6 V, T = 25 °C, f_{SYSCLK} < 14 MHz	—	226	—	µA/MHz
		V_{DD} = 1.8–3.6 V, T = 25 °C, f_{SYSCLK} > 14 MHz	—	120	—	µA/MHz
Idle Mode supply current - Core halted with peripherals running[4,6]	I_{DD}	V_{DD} = 1.8–3.6 V, f_{SYSCLK} = 24.5 MHz	—	2.5	3.0	mA
		V_{DD} = 1.8–3.6 V, f_{SYSCLK} = 20 MHz	—	1.8	—	mA
		V_{DD} = 1.8–3.6 V, f_{SYSCLK} = 32.768 kHz	—	84	—	µA
Idle Mode Supply Current Frequency Sensitivity[1,6]	I_{DDFREQ}	V_{DD} = 1.8–3.6 V, T = 25 °C	—	95	—	µA/MHz
Suspend Mode Supply Current	I_{DD}	V_{DD} = 1.8–3.6 V	—	77	—	µA
Sleep Mode Supply Current with RTC running from 32.768 kHz crystal	I_{DD}	1.8 V, T = 25 °C	—	0.60	—	µA
		3.6 V, T = 25 °C	—	0.85	—	µA
		1.8 V, T = 85 °C	—	1.30	—	µA
		3.6 V, T = 85 °C	—	1.90	—	µA

Parameter	Symbol	Conditions	Min	Typ	Max	Units
Sleep Mode Supply Current (RTC off)	I_{DD}	1.8 V, T = 25 °C	—	0.05	—	µA
		3.6 V, T = 25 °C	—	0.12	—	µA
		1.8 V, T = 85 °C	—	0.75	—	µA
		3.6 V, T = 85 °C	—	1.20	—	µA
V_{DD} Monitor Supply Current	I_{VMON}		—	7	—	µA
Oscillator Supply Current	I_{HFOSC0}	25 °C	—	300	—	µA
ADC0 Always-on Power Supply Current[7]	I_{ADC}	300 ksps V_{DD} = 3.0 V	—	800	—	µA
		Tracking V_{DD} = 3.0 V	—	680	—	µA
Comparator 0 (CMP0) Supply Current	I_{CMP}	CPMD = 11	—	0.4	—	µA
		CPMD = 10	—	2.6	—	µA
		CPMD = 01	—	8.8	—	µA
		CPMD = 00	—	23	—	µA
Internal Fast-settling 1.65V ADC0 Reference, Always-on[8]	I_{VREFFS}		—	200	—	µA
On-chip Precision Reference	I_{VREFP}		—	15	—	µA
Temp sensor Supply Current	I_{TSENSE}		—	35	—	µA
Programmable Current Reference (IREF0) Supply Current[9]	I_{IREF}	Current Source, Either Power Mode, Any Output Code	—	10	—	µA
		Low Power Mode, Current Sink IREF0DAT = 000001	—	1	—	µA
		Low Power Mode, Current Sink IREF0DAT = 111111	—	11	—	µA
		High Current Mode, Current Sink IREF0DAT = 000001	—	12	—	µA
		High Current Mode, Current Sink IREF0DAT = 111111	—	81	—	µA

Parameter	Symbol	Conditions	Min	Typ	Max	Units

Note:

1. Based on device characterization data; Not production tested.

2. SYSCLK must be at least 32 kHz to enable debugging.

3. Digital Supply Current depends upon the particular code being executed. The values in this table are obtained with the CPU executing an "sjmp $" loop, which is the compiled form of a while(1) loop in C. One iteration requires 3 CPU clock cycles, and the flash memory is read on each cycle. The supply current will vary slightly based on the physical location of the sjmp instruction and the number of flash address lines that toggle as a result. In the worst case, current can increase by up to 30% if the sjmp loop straddles a 128-byte flash address boundary (e.g., 0x007F to 0x0080). Real-world code with larger loops and longer linear sequences will have few transitions across the 128-byte address boundaries.

4. Includes supply current from regulator and oscillator source (24.5 MHz high-frequency oscillator, 20 MHz low-power oscillator, or 32.768 kHz RTC oscillator).

5. IDD can be estimated for frequencies < 10 MHz by simply multiplying the frequency of interest by the frequency sensitivity number for that range, then adding an offset of 90 µA. When using these numbers to estimate I_{DD} for > 10 MHz, the estimate should be the current at 25 MHz minus the difference in current indicated by the frequency sensitivity number. For example: V_{DD} = 3.0 V; F = 20 MHz, I_{DD} = 4.1 mA – (25 MHz – 20 MHz) x 0.120 mA/MHz = 3.5 mA assuming the same oscillator setting.

6. Idle IDD can be estimated by taking the current at 25 MHz minus the difference in current indicated by the frequency sensitivity number. For example: V_{DD} = 3.0 V; F = 5 MHz, Idle I_{DD} = 2.5 mA – (25 MHz – 5 MHz) x 0.095 mA/MHz = 0.6 mA.

7. ADC0 always-on power excludes internal reference supply current.

8. The internal reference is enabled as-needed when operating the ADC in burst mode to save power.

9. IREF0 supply current only. Does not include current sourced or sunk from IREF0 output pin.

Table 4.3. Reset and Supply Monitor

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
VDD Supply Monitor Threshold	V_{VDDM}	Reset Trigger	1.7	1.75	1.8	V
	V_{WARN}	Early Warning	1.8	1.85	1.9	V
VDD Supply Monitor Turn-On Time	t_{MON}		—	300	—	ns
Power-On Reset (POR) Monitor Threshold	V_{POR}	Initial Power-On (Rising Voltage on V_{DD})	—	0.75	—	V
		Falling Voltage on V_{DD}	0.7	0.8	0.9	V
		Brownout Recovery (Rising Voltage on V_{DD})	—	0.95	—	V
V_{DD} Ramp Time	t_{RMP}	Time to V_{DD} ≥ 1.8 V	—	—	3	ms
Reset Delay	t_{RST}	Time between release of reset source and code execution	—	10	—	µs
RST Low Time to Generate Reset	t_{RSTL}		15	—	—	µs
Missing Clock Detector Response Time (final rising edge to reset)	t_{MCD}	F_{SYSCLK} > 1 MHz	100	650	1000	µs
Missing Clock Detector Trigger Frequency	F_{MCD}		—	7	10	kHz

Table 4.4. Flash Memory

Parameter	Symbol	Test Condition	Min	Typ	Max	Units
Write Time[1]	t_{WRITE}	One Byte	57	64	71	µs
Erase Time[1]	t_{ERASE}	One Page	28	32	36	ms

Parameter	Symbol	Test Condition	Min	Typ	Max	Units
Endurance (Write/Erase Cycles)	N_{WE}		1 k	30 k	—	Cycles

Note:
1. Does not include sequencing time before and after the write/erase operation, which may be multiple SYSCLK cycles.
2. Data Retention Information is published in the Quarterly Quality and Reliability Report.

Table 4.5. Power Management Timing

Parameter	Symbol	Test Condition	Min	Typ	Max	Units
Idle Mode Wake-up Time	t_{IDLEWK}		2	—	3	SYSCLKs
Suspend Mode Wake-up Time	$t_{SUS-PENDWK}$	CLKDIV = 0x00 Precision Osc.	—	400	—	ns
		CLKDIV = 0x00 Low Power Osc.	—	1.3	—	µs
Sleep Mode Wake-up Time	$t_{SLEEPWK}$		—	2	—	µs

Table 4.6. Internal Oscillators

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
High Frequency Oscillator 0 (24.5 MHz)						
Oscillator Frequency	f_{HFOSC0}	Full Temperature and Supply Range	24	24.5	25	MHz
Low Power Oscillator (20 MHz)						
Oscillator Frequency	f_{LPOSC}	Full Temperature and Supply Range	18	20	22	MHz
RTC in Self-Oscillate Mode						
Oscillator Frequency	f_{LFOSC}	Bias Off	—	12 ± 5	—	kHz
		Bias On	—	25 ± 10	—	kHz

Table 4.7. Crystal Oscillator

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Crystal Frequency	f_{XTAL}		0.02	-	25	MHz

Table 4.8. External Clock Input

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
External Input CMOS Clock Frequency (at EXTCLK pin)	f_{CMOS}		0	—	25	MHz
External Input CMOS Clock High Time	t_{CMOSH}		18	—	—	ns
External Input CMOS Clock Low Time	t_{CMOSL}		18	—	—	ns

Table 4.9. ADC

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Resolution	N_{bits}			10		Bits
Throughput Rate	f_S		—	—	300	ksps
Tracking Time	t_{TRK}		1.5	—	—	µs
Power-On Time	t_{PWR}		1.5	—	—	µs
SAR Clock Frequency	f_{SAR}	High Speed Mode,	—	—	8.33	MHz
Conversion Time	T_{CNV}		13	—	—	Clocks
Sample/Hold Capacitor	C_{SAR}	Gain = 1	—	30	—	pF
		Gain = 0.5	—	28	—	pF
Input Pin Capacitance	C_{IN}		—	20	—	pF
Input Mux Impedance	R_{MUX}		—	5	—	kΩ
Voltage Reference Range	V_{REF}		1	—	V_{DD}	V
Input Voltage Range[1]	V_{IN}	Gain = 1	0	—	V_{REF}	V
		Gain = 0.5	0	—	$2 \times V_{REF}$	V
Power Supply Rejection Ratio	$PSRR_{ADC}$	Internal High Speed VREF	—	67	—	dB
		External VREF	—	74	—	dB
DC Performance						
Integral Nonlinearity	INL		—	±0.5	±1	LSB
Differential Nonlinearity (Guaranteed Monotonic)	DNL		—	±0.5	±1	LSB
Offset Error	E_{OFF}	VREF = 1.65 V	–2	0	2	LSB
Offset Temperature Coefficient	TC_{OFF}		—	0.004	—	LSB/°C
Slope Error	E_M		—	±0.06	±0.24	%
Dynamic Performance 10 kHz Sine Wave Input 1dB below full scale, Max throughput						
Signal-to-Noise	SNR		54	58	—	dB
Signal-to-Noise Plus Distortion	SNDR		54	58	—	dB
Total Harmonic Distortion (Up to 5th Harmonic)	THD		—	-73	—	dB
Spurious-Free Dynamic Range	SFDR		—	75	—	dB

Note:
1. Absolute input pin voltage is limited by the V_{DD} supply.

Table 4.10. Voltage References

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Internal Fast Settling Reference						
Output Voltage	V_{REFFS}		1.60	1.65	1.70	V

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Temperature Coefficient	TC_{REFFS}		—	50	—	ppm/°C
Turn-on Time	t_{VREFFS}		—	—	1.5	µs
Power Supply Rejection	$PSRR_{REFFS}$		—	400	—	ppm/V
On-chip Precision Reference						
Output Voltage	V_{REFP}		1.645	1.68	1.715	V
Turn-on Time, settling to 0.5 LSB	t_{VREFP}	4.7 µF tantalum + 0.1 µF ceramic bypass on VREF pin	—	15	—	ms
		0.1 µF ceramic bypass on VREF pin	—	300	—	µs
		No bypass on VREF pin	—	25	—	µs
Load Regulation	LR_{VREFP}	Load = 0 to 200 µA to GND	—	400	—	µV / µA
Short-circuit current	ISC_{VREFP}		—	3.5	—	mA
Power Supply Rejection	$PSRR_{VREFP}$		—	140	—	ppm/V
External Reference						
Input Voltage	V_{EXTREF}		1	—	V_{DD}	V
Input Current	I_{EXTREF}	Sample Rate = 300 ksps; VREF = 3.0 V	—	5.25	—	µA

Table 4.11. Temperature Sensor

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Offset	V_{OFF}	T_A = 0 °C	—	940	—	mV
Offset Error[1]	E_{OFF}	T_A = 0 °C	—	18	—	mV
Slope	M		—	3.40	—	mV/°C
Slope Error[1]	E_M		—	40	—	µV/°C
Linearity			—	±1	—	°C
Turn-on Time	t_{PWR}		—	1.8	—	µs

Note:
1. Represents one standard deviation from the mean.

Table 4.12. Comparators

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Response Time, CPMD = 00 (Highest Speed)	t_{RESP0}	+100 mV Differential	—	130	—	ns
		−100 mV Differential	—	200	—	ns
Response Time, CPMD = 11 (Lowest Power)	t_{RESP3}	+100 mV Differential	—	1.75	—	µs
		−100 mV Differential	—	6.2	—	µs

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Positive Hysterisis Mode 0 (CPMD = 00)	HYS_{CP+}	CPHYP = 00	—	0.4	—	mV
		CPHYP = 01	—	8	—	mV
		CPHYP = 10	—	16	—	mV
		CPHYP = 11	—	32	—	mV
Negative Hysterisis Mode 0 (CPMD = 00)	HYS_{CP-}	CPHYN = 00	—	-0.4	—	mV
		CPHYN = 01	—	–8	—	mV
		CPHYN = 10	—	–16	—	mV
		CPHYN = 11	—	–32	—	mV
Positive Hysterisis Mode 1 (CPMD = 01)	HYS_{CP+}	CPHYP = 00	—	0.5	—	mV
		CPHYP = 01	—	6	—	mV
		CPHYP = 10	—	12	—	mV
		CPHYP = 11	—	24	—	mV
Negative Hysterisis Mode 1 (CPMD = 01)	HYS_{CP-}	CPHYN = 00	—	-0.5	—	mV
		CPHYN = 01	—	–6	—	mV
		CPHYN = 10	—	–12	—	mV
		CPHYN = 11	—	–24	—	mV
Positive Hysterisis Mode 2 (CPMD = 10)	HYS_{CP+}	CPHYP = 00	—	0.7	—	mV
		CPHYP = 01	—	4.5	—	mV
		CPHYP = 10	—	9	—	mV
		CPHYP = 11	—	18	—	mV
Negative Hysterisis Mode 2 (CPMD = 10)	HYS_{CP-}	CPHYN = 00	—	-0.6	—	mV
		CPHYN = 01	—	–4.5	—	mV
		CPHYN = 10	—	–9	—	mV
		CPHYN = 11	—	–18	—	mV
Positive Hysteresis Mode 3 (CPMD = 11)	HYS_{CP+}	CPHYP = 00	—	1.5	—	mV
		CPHYP = 01	—	4	—	mV
		CPHYP = 10	—	8	—	mV
		CPHYP = 11	—	16	—	mV
Negative Hysteresis Mode 3 (CPMD = 11)	HYS_{CP-}	CPHYN = 00	—	-1.5	—	mV
		CPHYN = 01	—	–4	—	mV
		CPHYN = 10	—	–8	—	mV
		CPHYN = 11	—	–16	—	mV
Input Range (CP+ or CP–)	V_{IN}		-0.25	—	V_{DD}+0.25	V
Input Pin Capacitance	C_{CP}		—	12	—	pF
Common-Mode Rejection Ratio	$CMRR_{CP}$		—	70	—	dB
Power Supply Rejection Ratio	$PSRR_{CP}$		—	72	—	dB
Input Offset Voltage	V_{OFF}	T_A = 25 °C	-10	0	10	mV

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Input Offset Tempco	TC_{OFF}		—	3.5	—	µV/°C

Table 4.13. Programmable Current Reference (IREF0)

Parameter	Symbol	Conditions	Min	Typ	Max	Units
Static Performance						
Resolution	N_{bits}			6		bits
Output Compliance Range	V_{IOUT}	Low Power Mode, Source	0	—	$V_{DD} - 0.4$	V
		High Current Mode, Source	0	—	$V_{DD} - 0.8$	V
		Low Power Mode, Sink	0.3	—	V_{DD}	V
		High Current Mode, Sink	0.8	—	V_{DD}	V
Integral Nonlinearity	INL		—	$<\pm0.2$	±1.0	LSB
Differential Nonlinearity	DNL		—	$<\pm0.2$	±1.0	LSB
Offset Error	E_{OFF}		—	$<\pm0.1$	±0.5	LSB
Full Scale Error	E_{FS}	Low Power Mode, Source	—	—	±5	%
		High Current Mode, Source	—	—	±6	%
		Low Power Mode, Sink	—	—	±8	%
		High Current Mode, Sink	—	—	±8	%
Absolute Current Error	E_{ABS}	Low Power Mode Sourcing 20 µA	—	$<\pm1$	±3	%
Dynamic Performance						
Output Settling Time to 1/2 LSB	t_{SETTLE}		—	300	—	ns
Startup Time	t_{PWR}		—	1	—	µs

Note:
1. The PCA block may be used to improve IREF0 resolution by PWMing the two LSBs.

Table 4.14. Port I/O

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Output High Voltage (High Drive)	V_{OH}	$I_{OH} = -3$ mA	$V_{DD} - 0.7$	—	—	V
Output Low Voltage (High Drive)	V_{OL}	$I_{OL} = 8.5$ mA	—	—	0.6	V
Output High Voltage (Low Drive)	V_{OH}	$I_{OH} = -1$ mA	$V_{DD} - 0.7$	—	—	V
Output Low Voltage (Low Drive)	V_{OL}	$I_{OL} = 1.4$ mA	—	—	0.6	V
Input High Voltage	V_{IH}	V_{DD} = 2.0 to 3.6 V	$V_{DD} - 0.6$	—	—	V
		V_{DD} = 1.8 to 2.0 V	$0.7 \times V_{DD}$	—	—	V
Input Low Voltage	V_{IL}	V_{DD} = 2.0 to 3.6 V	—	—	0.6	V
		V_{DD} = 1.8 to 2.0 V	—	—	$0.3 \times V_{DD}$	V

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Weak Pull-Up Current	I_{PU}	V_{DD} = 1.8 V V_{IN} = 0 V	—	–4	—	µA
		V_{DD} = 3.6 V V_{IN} = 0 V	–35	–20	—	µA
Input Leakage	I_{LK}	Weak pullup disabled or pin in analog mode	–1	—	1	µA

4.2 Thermal Conditions

Table 4.15. Thermal Conditions

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Thermal Resistance[1]	θ_{JA}	QFN-24 Packages	—	35	—	°C/W
		QFN-32 Packages	—	28	—	°C/W
		QFP-32 Packages	—	80	—	°C/W
Note: 1. Thermal resistance assumes a multi-layer PCB with any exposed pad soldered to a PCB pad.						

4.3 Absolute Maximum Ratings

Stresses above those listed in Table 4.16 Absolute Maximum Ratings on page 19 may cause permanent damage to the device. This is a stress rating only and functional operation of the devices at those or any other conditions above those indicated in the operation listings of this specification is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability. For more information on the available quality and reliability data, see the Quality and Reliability Monitor Report at http://www.silabs.com/support/quality/pages/default.aspx.

Table 4.16. Absolute Maximum Ratings

Parameter	Symbol	Test Condition	Min	Max	Unit
Ambient Temperature Under Bias	T_{BIAS}		–55	125	°C
Storage Temperature	T_{STG}		–65	150	°C
Voltage on V_{DD}	V_{DD}		GND–0.3	4.0	V
Voltage on I/O pins or RSTb	V_{IN}	V_{DD} > 2.2 V	GND–0.3	5.8	V
		V_{DD} <= 2.2 V	GND–0.3	V_{DD} + 3.6	V
Total Current Sunk into Supply Pin	I_{VDD}		—	400	mA
Total Current Sourced out of Ground Pin	I_{GND}		400	—	mA
Current Sourced or Sunk by Any I/O Pin or RSTb	I_{IO}		-100	100	mA
Maximum Total Current through all Port Pins	I_{IOTOT}		—	200	mA
Operating Junction Temperature	T_J		–40	105	°C
Exposure to maximum rating conditions for extended periods may affect device reliability.					

4.4 Typical Performance Curves
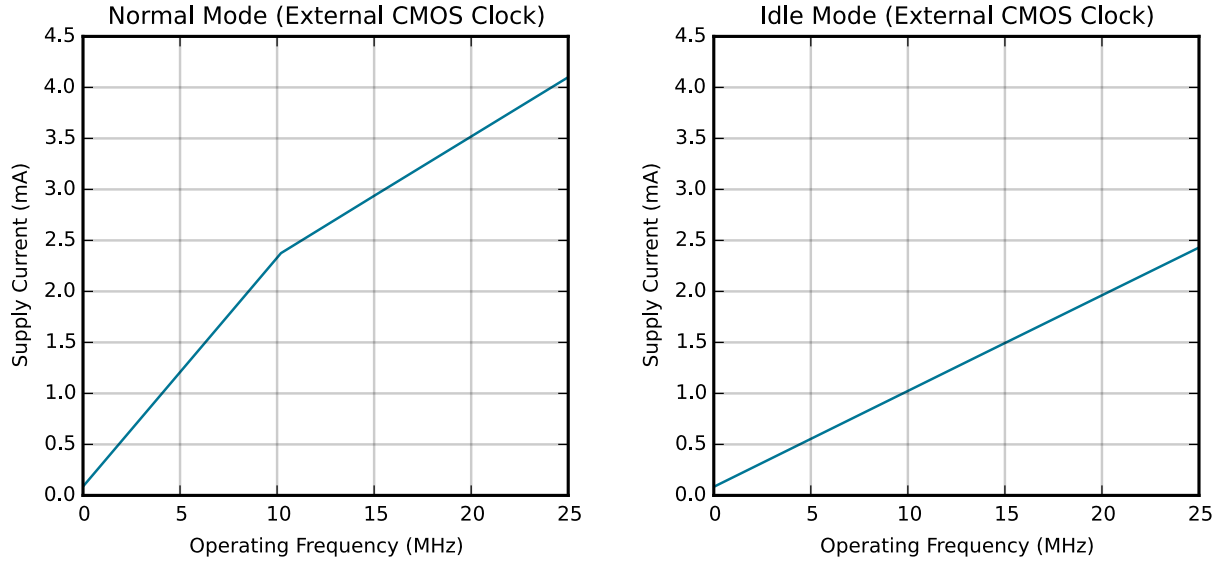
Figure 4.1. Typical Operating Supply Current (full supply voltage range)
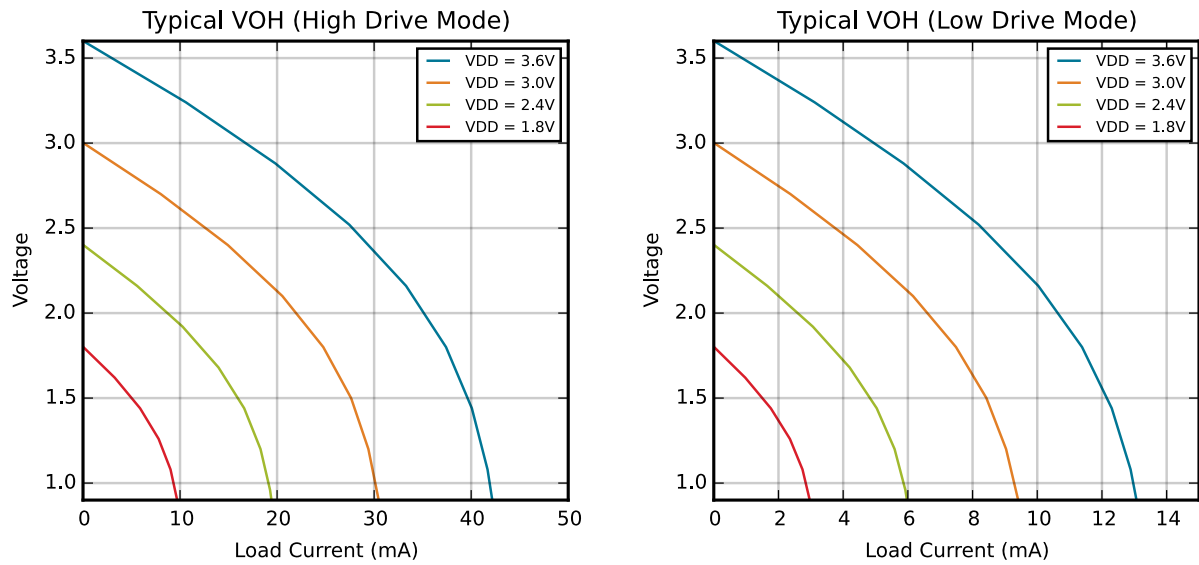
Figure 4.2. Typical V_{OH} Curves
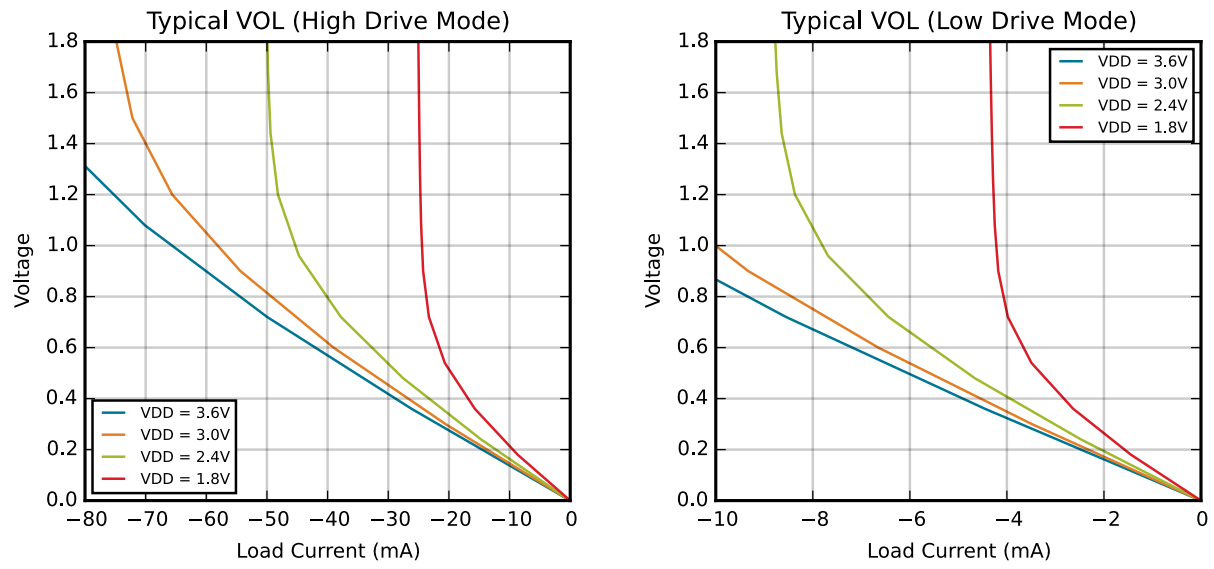
Figure 4.3. Typical V$_{OL}$ Curves

5. Typical Connection Diagrams

5.1 Power

shows a typical connection diagram for the power pins of the EFM8SB2 devices.

1 µF and 0.1 µF bypass capacitors required for the power pins placed as close to the pins as possible.

1.8-3.6 V (in)

VDD

GND

EFM8SB2 Device
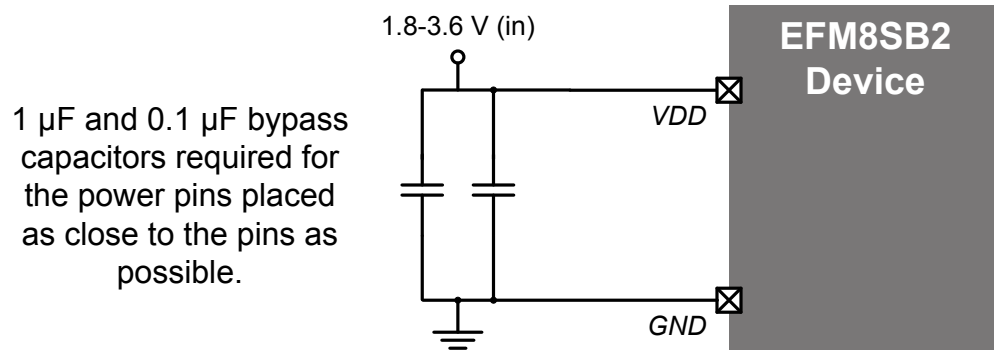
Figure 5.1. Power Connection Diagram

5.2 Other Connections

Other components or connections may be required to meet the system-level requirements. Application Note AN203: "8-bit MCU Printed Circuit Board Design Notes" contains detailed information on these connections. Application Notes can be accessed on the Silicon Labs website (www.silabs.com/8bit-appnotes).

6. Pin Definitions
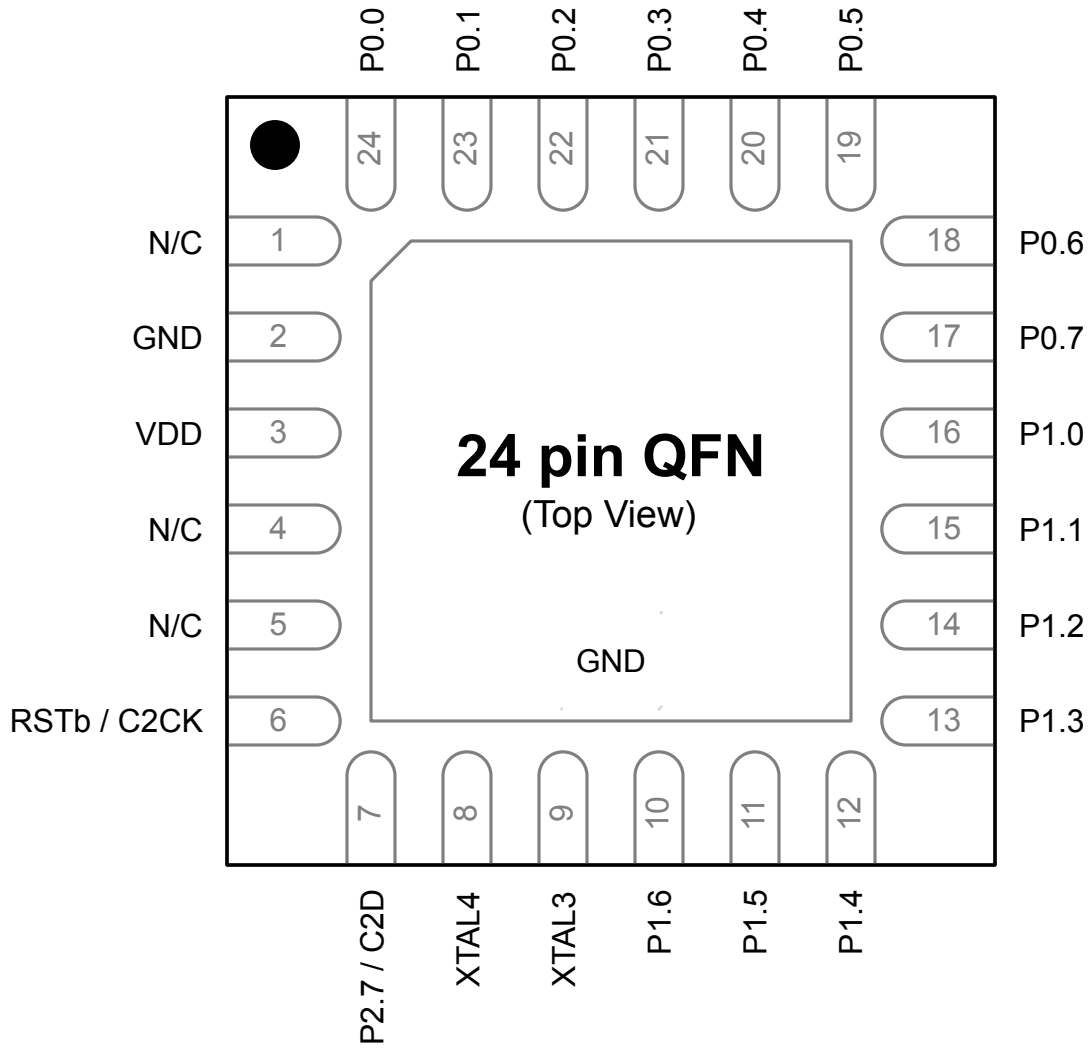
6.1 EFM8SB2x-QFN32 Pin Definitions
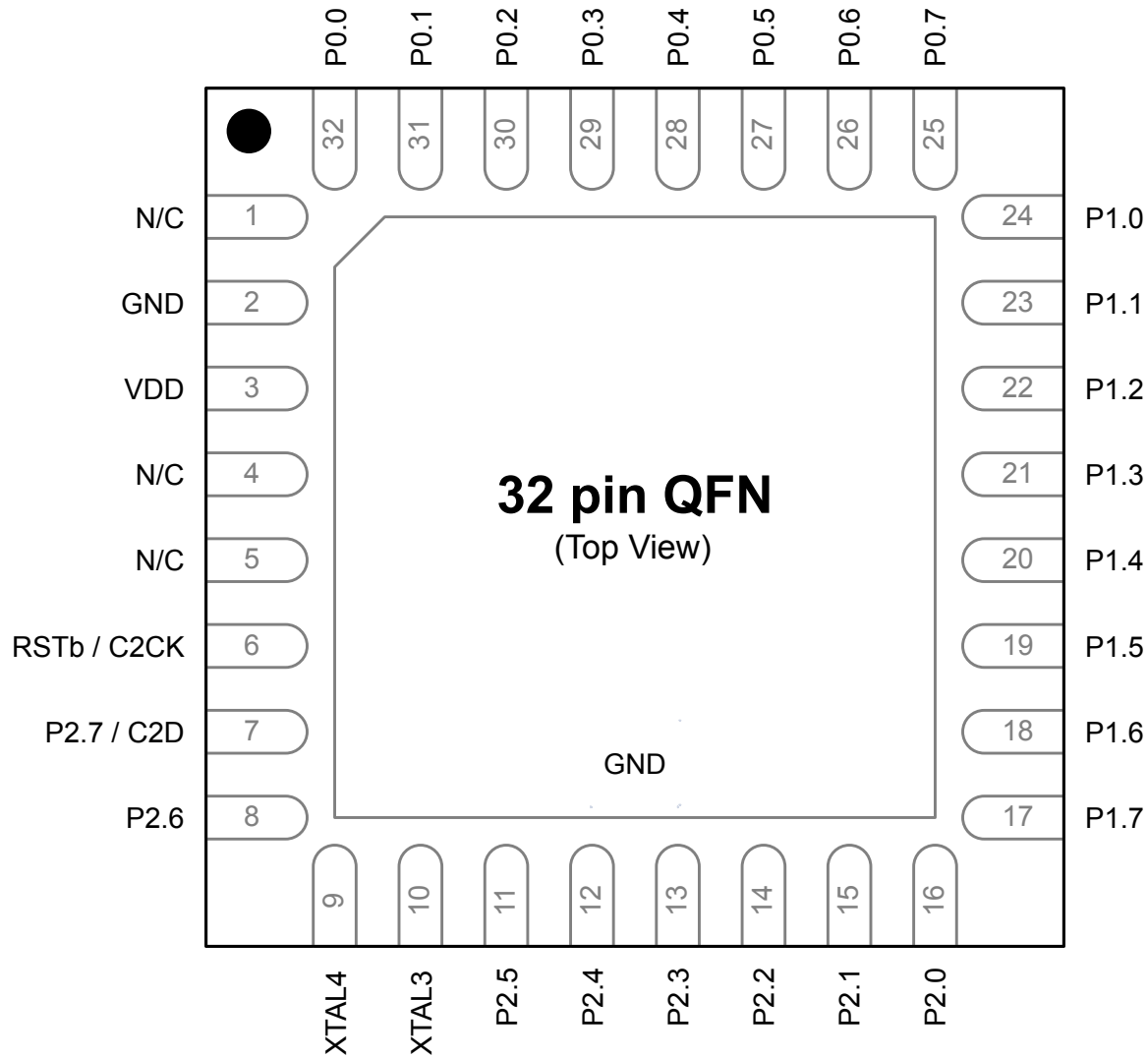
Figure 6.1. EFM8SB2x-QFN32 Pinout

Table 6.1. Pin Definitions for EFM8SB2x-QFN32

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
1	N/C	No Connection			
2	GND	Ground			
3	VDD	Supply Power Input			
4	N/C	No Connection			

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
5	N/C	No Connection			
6	RSTb / C2CK	Active-low Reset / C2 Debug Clock			
7	P2.7 / C2D	Multifunction I/O / C2 Debug Data			
8	P2.6	Multifunction I/O	Yes	EMIF_WRb	ADC0.22 CMP0P.11 CMP1P.11
9	XTAL4	RTC Crystal			XTAL4
10	XTAL3	RTC Crystal			XTAL3
11	P2.5	Multifunction I/O	Yes	EMIF_RDb	ADC0.21 CMP0N.10 CMP1N.10
12	P2.4	Multifunction I/O	Yes	EMIF_ALE	ADC0.20 CMP0P.10 CMP1P.10
13	P2.3	Multifunction I/O	Yes	EMIF_A11	ADC0.19 CMP0N.9 CMP1N.9
14	P2.2	Multifunction I/O	Yes	EMIF_A10	ADC0.18 CMP0P.9 CMP1P.9
15	P2.1	Multifunction I/O	Yes	EMIF_A9	ADC0.17 CMP0N.8 CMP1N.8
16	P2.0	Multifunction I/O	Yes	EMIF_A8	ADC0.16 CMP0P.8 CMP1P.8
17	P1.7	Multifunction I/O	Yes	P1MAT.7 EMIF_AD7	ADC0.15 CMP0N.7 CMP1N.7
18	P1.6	Multifunction I/O	Yes	P1MAT.6 EMIF_AD6	ADC0.14 CMP0P.7 CMP1P.7

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
19	P1.5	Multifunction I/O	Yes	P1MAT.5 EMIF_AD5	ADC0.13 CMP0N.6 CMP1N.6
20	P1.4	Multifunction I/O	Yes	P1MAT.4 EMIF_AD4	ADC0.12 CMP0P.6 CMP1P.6
21	P1.3	Multifunction I/O	Yes	P1MAT.3 SPI1_NSS EMIF_AD3	ADC0.11 CMP0N.5 CMP1N.5
22	P1.2	Multifunction I/O	Yes	P1MAT.2 SPI1_MOSI EMIF_AD2	ADC0.10 CMP0P.5 CMP1P.5
23	P1.1	Multifunction I/O	Yes	P1MAT.1 SPI1_MISO EMIF_AD1	ADC0.9 CMP0N.4 CMP1N.4
24	P1.0	Multifunction I/O	Yes	P1MAT.0 SPI1_SCK EMIF_AD0	ADC0.8 CMP0P.4 CMP1P.4
25	P0.7	Multifunction I/O	Yes	P0MAT.7 INT0.7 INT1.7	ADC0.7 IREF0 CMP0N.3 CMP1N.3
26	P0.6	Multifunction I/O	Yes	P0MAT.6 CNVSTR INT0.6 INT1.6	ADC0.6 CMP0P.3 CMP1P.3
27	P0.5	Multifunction I/O	Yes	P0MAT.5 INT0.5 INT1.5	ADC0.5 CMP0N.2 CMP1N.2
28	P0.4	Multifunction I/O	Yes	P0MAT.4 INT0.4 INT1.4	ADC0.4 CMP0P.2 CMP1P.2
29	P0.3	Multifunction I/O	Yes	P0MAT.3 EXTCLK INT0.3 INT1.3	ADC0.3 XTAL2 CMP0N.1 CMP1N.1

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
30	P0.2	Multifunction I/O	Yes	P0MAT.2 INT0.2 INT1.2	ADC0.2 CMP0P.1 CMP1P.1 XTAL1
31	P0.1	Multifunction I/O	Yes	P0MAT.1 INT0.1 INT1.1	ADC0.1 AGND CMP0N.0 CMP1N.0
32	P0.0	Multifunction I/O	Yes	P0MAT.0 INT0.0 INT1.0	ADC0.0 CMP0P.0 CMP1P.0 VREF
Center	GND	Ground			

6.2 EFM8SB2x-QFN24 Pin Definitions

Figure 6.2. EFM8SB2x-QFN24 Pinout

Table 6.2. Pin Definitions for EFM8SB2x-QFN24

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
1	N/C	No Connection			
2	GND	Ground			
3	VDD	Supply Power Input			
4	N/C	No Connection			
5	N/C	No Connection			

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
6	RSTb / C2CK	Active-low Reset / C2 Debug Clock			
7	P2.7 / C2D	Multifunction I/O / C2 Debug Data			
8	XTAL4	RTC Crystal			XTAL4
9	XTAL3	RTC Crystal			XTAL3
10	P1.6	Multifunction I/O	Yes		ADC0.14 CMP0P.7 CMP1P.7
11	P1.5	Multifunction I/O	Yes	P1MAT.5	ADC0.13 CMP0N.6 CMP1N.6
12	P1.4	Multifunction I/O	Yes	P1MAT.4	ADC0.12 CMP0P.6 CMP1P.6
13	P1.3	Multifunction I/O	Yes	P1MAT.3 SPI1_NSS	ADC0.11 CMP0N.5 CMP1N.5
14	P1.2	Multifunction I/O	Yes	P1MAT.2 SPI1_MOSI	ADC0.10 CMP0P.5 CMP1P.5
15	P1.1	Multifunction I/O	Yes	P1MAT.1 SPI1_MISO	ADC0.9 CMP0N.4 CMP1N.4
16	P1.0	Multifunction I/O	Yes	P1MAT.0 SPI1_SCK	ADC0.8 CMP0P.4 CMP1P.4
17	P0.7	Multifunction I/O	Yes	P0MAT.7 INT0.7 INT1.7	ADC0.7 IREF0 CMP0N.3 CMP1N.3
18	P0.6	Multifunction I/O	Yes	P0MAT.6 CNVSTR INT0.6 INT1.6	ADC0.6 CMP0P.3 CMP1P.3

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
19	P0.5	Multifunction I/O	Yes	P0MAT.5 INT0.5 INT1.5	ADC0.5 CMP0N.2 CMP1N.2
20	P0.4	Multifunction I/O	Yes	P0MAT.4 INT0.4 INT1.4	ADC0.4 CMP0P.2 CMP1P.2
21	P0.3	Multifunction I/O	Yes	P0MAT.3 EXTCLK INT0.3 INT1.3	ADC0.3 XTAL2 CMP0N.1 CMP1N.1
22	P0.2	Multifunction I/O	Yes	P0MAT.2 INT0.2 INT1.2	ADC0.2 CMP0P.1 CMP1P.1 XTAL1
23	P0.1	Multifunction I/O	Yes	P0MAT.1 INT0.1 INT1.1	ADC0.1 AGND CMP0N.0 CMP1N.0
24	P0.0	Multifunction I/O	Yes	P0MAT.0 INT0.0 INT1.0	ADC0.0 CMP0P.0 CMP1P.0 VREF
Center	GND	Ground			

6.3 EFM8SB2x-QFP32 Pin Definitions
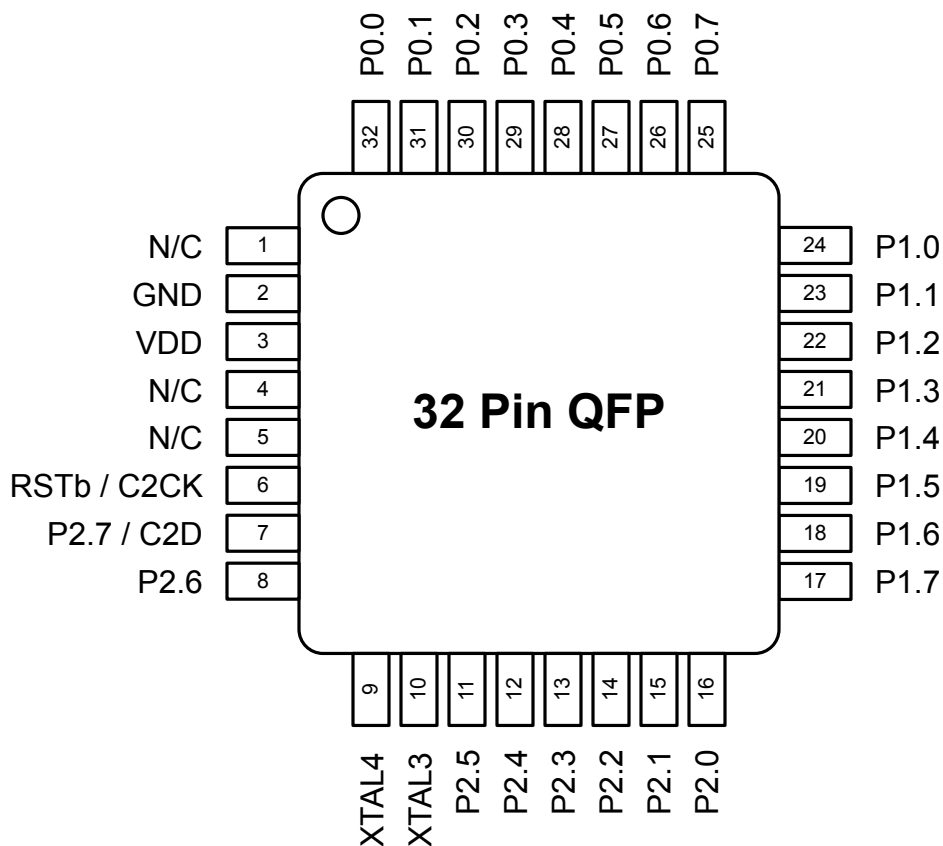
Figure 6.3. EFM8SB2x-QFP32 Pinout

Table 6.3. Pin Definitions for EFM8SB2x-QFP32

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
1	N/C	No Connection			
2	GND	Ground			
3	VDD	Supply Power Input			
4	N/C	No Connection			
5	N/C	No Connection			
6	RSTb / C2CK	Active-low Reset / C2 Debug Clock			
7	P2.7 / C2D	Multifunction I/O / C2 Debug Data			

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
8	P2.6	Multifunction I/O	Yes	EMIF_WRb	ADC0.22 CMP0P.11 CMP1P.11
9	XTAL4	RTC Crystal			XTAL4
10	XTAL3	RTC Crystal			XTAL3
11	P2.5	Multifunction I/O	Yes	EMIF_RDb	ADC0.21 CMP0N.10 CMP1N.10
12	P2.4	Multifunction I/O	Yes	EMIF_ALE	ADC0.20 CMP0P.10 CMP1P.10
13	P2.3	Multifunction I/O	Yes	EMIF_A11	ADC0.19 CMP0N.9 CMP1N.9
14	P2.2	Multifunction I/O	Yes	EMIF_A10	ADC0.18 CMP0P.9 CMP1P.9
15	P2.1	Multifunction I/O	Yes	EMIF_A9	ADC0.17 CMP0N.8 CMP1N.8
16	P2.0	Multifunction I/O	Yes	EMIF_A8	ADC0.16 CMP0P.8 CMP1P.8
17	P1.7	Multifunction I/O	Yes	P1MAT.7 EMIF_AD7	ADC0.15 CMP0N.7 CMP1N.7
18	P1.6	Multifunction I/O	Yes	P1MAT.6 EMIF_AD6	ADC0.14 CMP0P.7 CMP1P.7
19	P1.5	Multifunction I/O	Yes	P1MAT.5 EMIF_AD5	ADC0.13 CMP0N.6 CMP1N.6
20	P1.4	Multifunction I/O	Yes	P1MAT.4 EMIF_AD4	ADC0.12 CMP0P.6 CMP1P.6

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
21	P1.3	Multifunction I/O	Yes	P1MAT.3 SPI1_NSS EMIF_AD3	ADC0.11 CMP0N.5 CMP1N.5
22	P1.2	Multifunction I/O	Yes	P1MAT.2 SPI1_MOSI EMIF_AD2	ADC0.10 CMP0P.5 CMP1P.5
23	P1.1	Multifunction I/O	Yes	P1MAT.1 SPI1_MISO EMIF_AD1	ADC0.9 CMP0N.4 CMP1N.4
24	P1.0	Multifunction I/O	Yes	P1MAT.0 SPI1_SCK EMIF_AD0	ADC0.8 CMP0P.4 CMP1P.4
25	P0.7	Multifunction I/O	Yes	P0MAT.7 INT0.7 INT1.7	ADC0.7 IREF0 CMP0N.3 CMP1N.3
26	P0.6	Multifunction I/O	Yes	P0MAT.6 CNVSTR INT0.6 INT1.6	ADC0.6 CMP0P.3 CMP1P.3
27	P0.5	Multifunction I/O	Yes	P0MAT.5 INT0.5 INT1.5	ADC0.5 CMP0N.2 CMP1N.2
28	P0.4	Multifunction I/O	Yes	P0MAT.4 INT0.4 INT1.4	ADC0.4 CMP0P.2 CMP1P.2
29	P0.3	Multifunction I/O	Yes	P0MAT.3 EXTCLK INT0.3 INT1.3	ADC0.3 XTAL2 CMP0N.1 CMP1N.1
30	P0.2	Multifunction I/O	Yes	P0MAT.2 INT0.2 INT1.2	ADC0.2 CMP0P.1 CMP1P.1 XTAL1

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
31	P0.1	Multifunction I/O	Yes	P0MAT.1 INT0.1 INT1.1	ADC0.1 AGND CMP0N.0 CMP1N.0
32	P0.0	Multifunction I/O	Yes	P0MAT.0 INT0.0 INT1.0	ADC0.0 CMP0P.0 CMP1P.0 VREF

7. QFN32 Package Specifications

7.1 QFN32 Package Dimensions
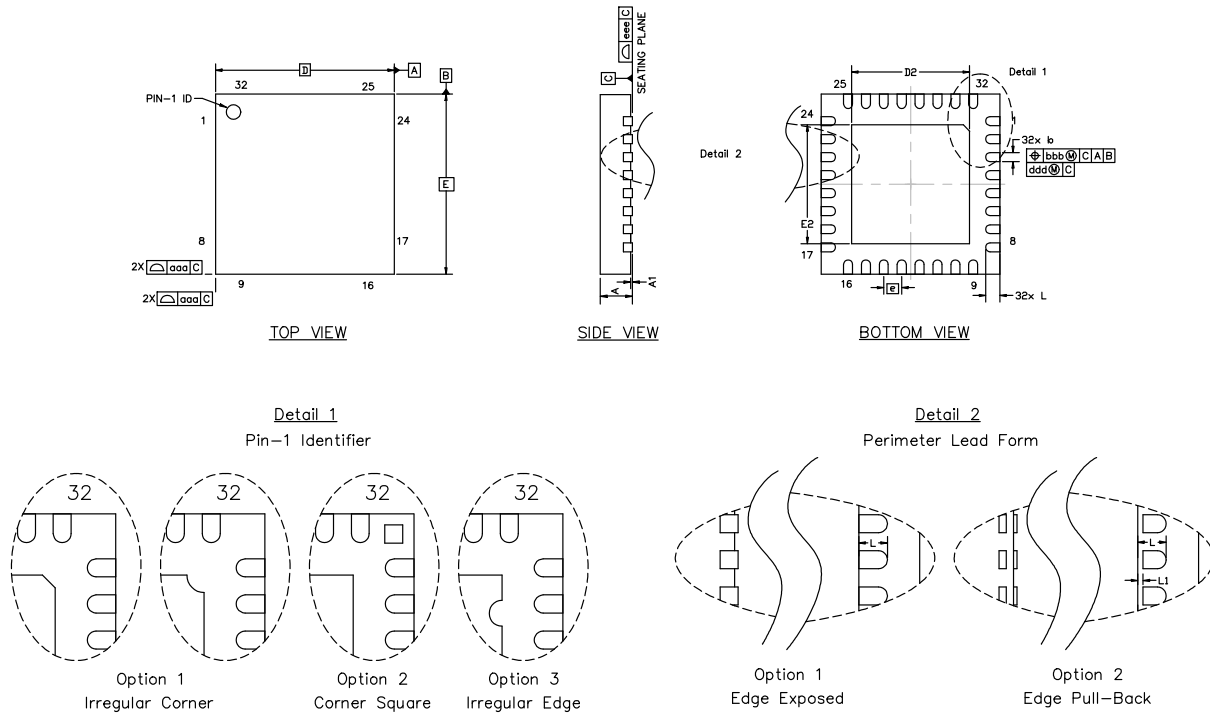
Figure 7.1. QFN32 Package Drawing

Table 7.1. QFN32 Package Dimensions

Dimension	Min	Typ	Max
A	0.80	0.90	1.00
A1	0.00	0.02	0.05
b	0.18	0.25	0.30
D		5.00 BSC	
D2	3.20	3.30	3.40
e		0.50 BSC	
E		5.00 BSC	
E2	3.20	3.30	3.40
L	0.30	0.40	0.50
L1	0.00	—	0.15
aaa	—	—	0.15

Dimension	Min	Typ	Max
bbb	—	—	0.10
ddd	—	—	0.05
eee	—	—	0.08

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. This drawing conforms to JEDEC Solid State Outline MO-220, variation VHHD except for custom features D2, E2, and L which are toleranced per supplier designation.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020C specification for Small Body Components.

7.2 QFN32 PCB Land Pattern
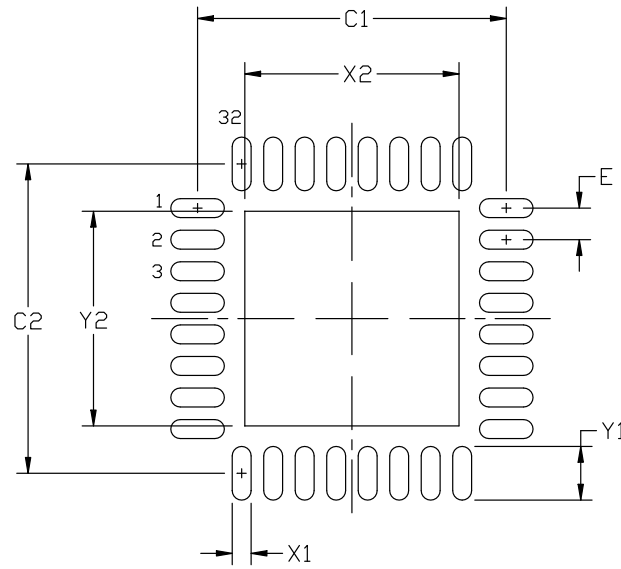
Figure 7.2. QFN32 PCB Land Pattern Drawing

Table 7.2. QFN32 PCB Land Pattern Dimensions

Dimension	Min	Max
C1	4.80	4.90
C2	4.80	4.90
E	0.50 BSC	
X1	0.20	0.30
X2	3.20	3.40
Y1	0.75	0.85
Y2	3.20	3.40

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. This Land Pattern Design is based on the IPC-7351 guidelines.
3. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 μm minimum, all the way around the pad.
4. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.
5. The stencil thickness should be 0.125 mm (5 mils).
6. The ratio of stencil aperture to land pad size should be 1:1 for all perimeter pads.
7. A 3 x 3 array of 1.0 mm x 1.0 mm openings on a 1.2 mm pitch should be used for the center pad.
8. A No-Clean, Type-3 solder paste is recommended.
9. The recommended card reflow profile is per the JEDEC/IPC J-STD-020C specification for Small Body Components.

7.3 QFN32 Package Marking

Figure 7.3. QFN32 Package Marking

The package marking consists of:
- PPPPPPPP – The part number designation.
- TTTTTT – A trace or manufacturing code.
- YY – The last 2 digits of the assembly year.
- WW – The 2-digit workweek when the device was assembled.
- # – The device revision (A, B, etc.).

# 8. QFN24 Package Specifications

8.1 QFN24 Package Dimensions
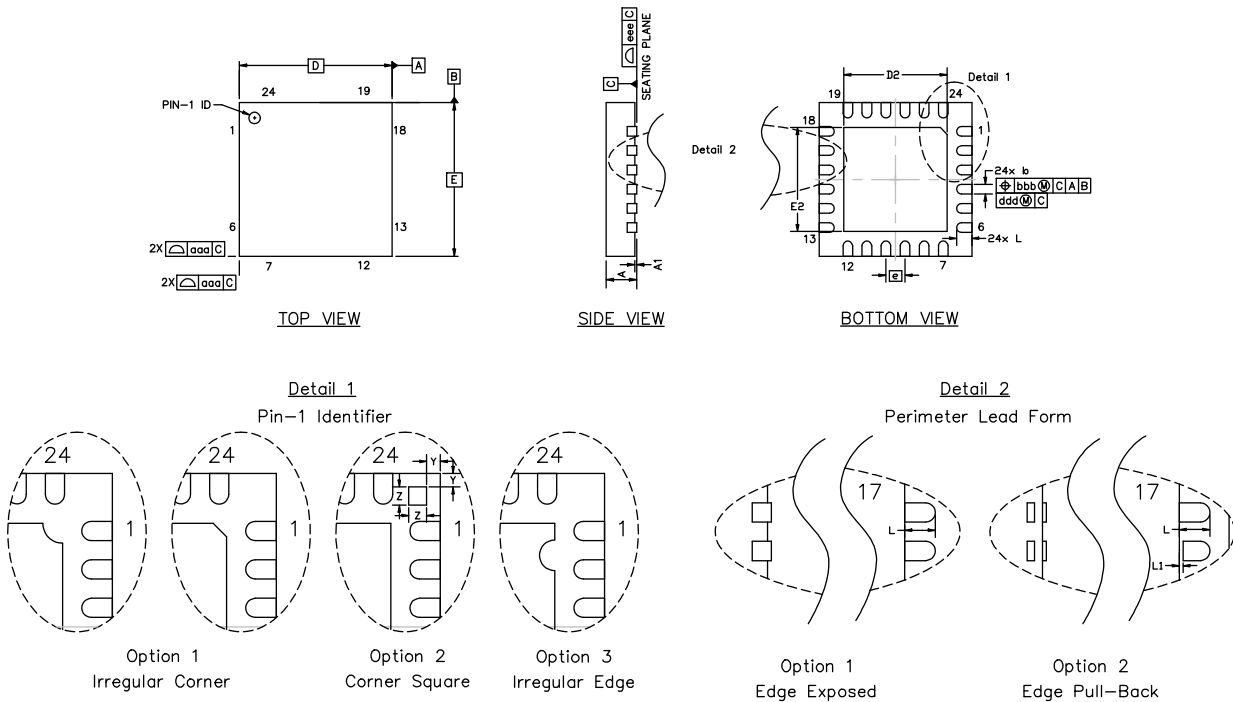
Figure 8.1. QFN24 Package Drawing

Table 8.1. QFN24 Package Dimensions

Dimension	Min	Typ	Max
A	0.70	0.75	0.80
A1	0.00	0.02	0.05
b	0.18	0.25	0.30
D	4.00 BSC		
D2	2.55	2.70	2.80
e	0.50 BSC		
E	4.00 BSC		
E2	2.55	2.70	2.80
L	0.30	0.40	0.50
L1	0.00	—	0.15
aaa	—	—	0.15

Dimension	Min	Typ	Max
bbb	—	—	0.10
ddd	—	—	0.05
eee	—	—	0.08
Z	—	0.24	—
Y	—	0.18	—

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. This drawing conforms to JEDEC Solid State Outline MO-220, variation WGGD except for custom features D2, E2, Z, Y, and L which are toleranced per supplier designation.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020C specification for Small Body Components.

8.2 QFN24 PCB Land Pattern
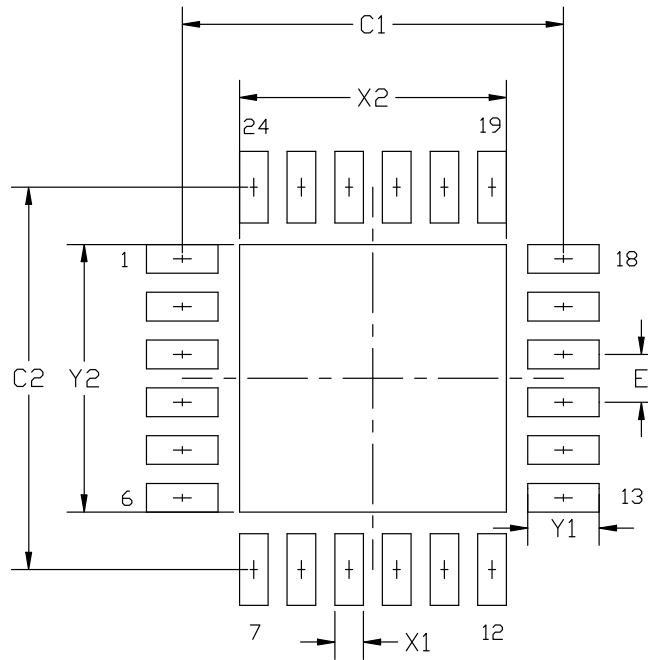
**Figure 8.2. QFN24 PCB Land Pattern Drawing**

Table 8.2. QFN24 PCB Land Pattern Dimensions

Dimension	Min	Max
C1	3.90	4.00
C2	3.90	4.00
E	0.50 BSC	
X1	0.20	0.30
X2	2.70	2.80
Y1	0.65	0.75
Y2	2.70	2.80

Dimension	Min	Max

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. This Land Pattern Design is based on the IPC-7351 guidelines.
3. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 µm minimum, all the way around the pad.
4. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.
5. The stencil thickness should be 0.125 mm (5 mils).
6. The ratio of stencil aperture to land pad size should be 1:1 for all perimeter pads.
7. A 2 x 2 array of 1.10 mm x 1.10 mm openings on 1.30 mm pitch should be used for the center ground pad.
8. A No-Clean, Type-3 solder paste is recommended.
9. The recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

8.3 QFN24 Package Marking

Figure 8.3. QFN24 Package Marking

The package marking consists of:

- PPPPPPPP – The part number designation.
- TTTTTT – A trace or manufacturing code.
- YY – The last 2 digits of the assembly year.
- WW – The 2-digit workweek when the device was assembled.
- # – The device revision (A, B, etc.).

9. QFP32 Package Specifications

9.1 QFP32 Package Dimensions
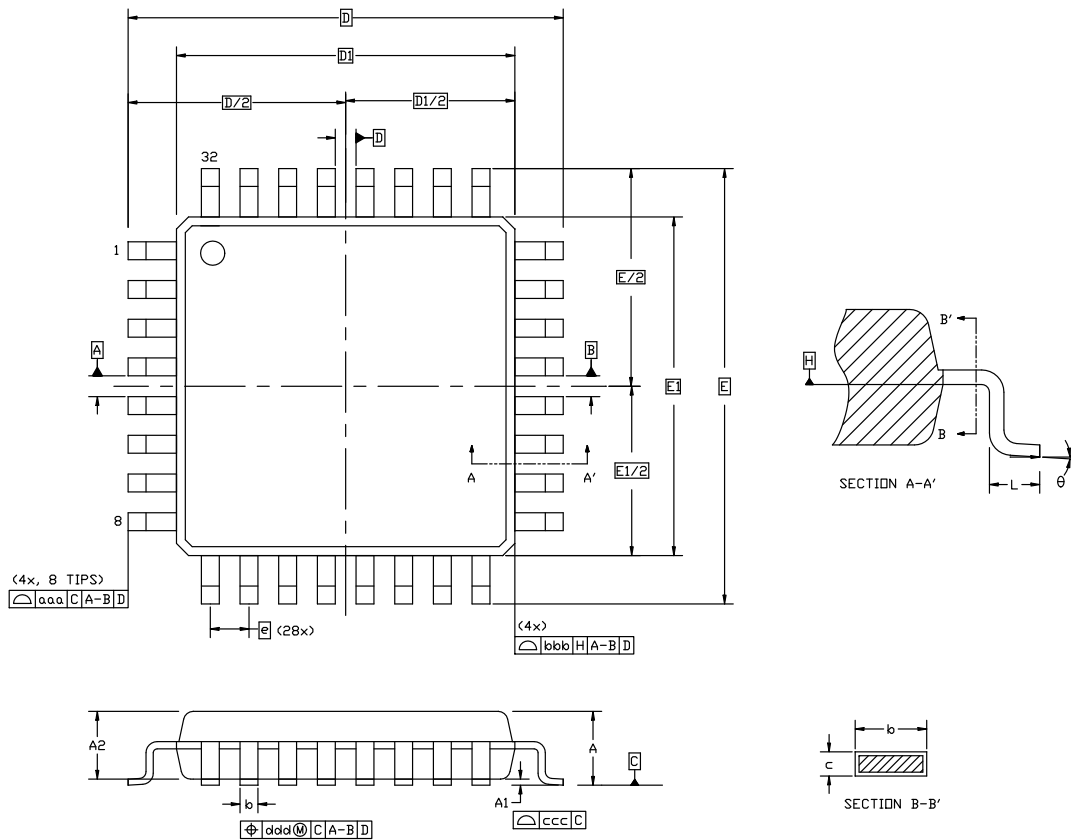
Figure 9.1. QFP32 Package Drawing

Table 9.1. QFP32 Package Dimensions

Dimension	Min	Typ	Max
A	—	—	1.60
A1	0.05	—	0.15
A2	1.35	1.40	1.45
b	0.30	0.37	0.45
D	9.00 BSC		
D1	7.00 BSC		
e	0.80 BSC		
E	9.00 BSC		
E1	7.00 BSC		
L	0.45	0.60	0.75
aaa	0.20		

Dimension	Min	Typ	Max
bbb		0.20	
ccc		0.10	
ddd		0.20	
theta	0°	3.5°	7°

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. This drawing conforms to JEDEC outline MS-026, variation BBA.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020C specification for Small Body Components.

9.2 QFP32 PCB Land Pattern
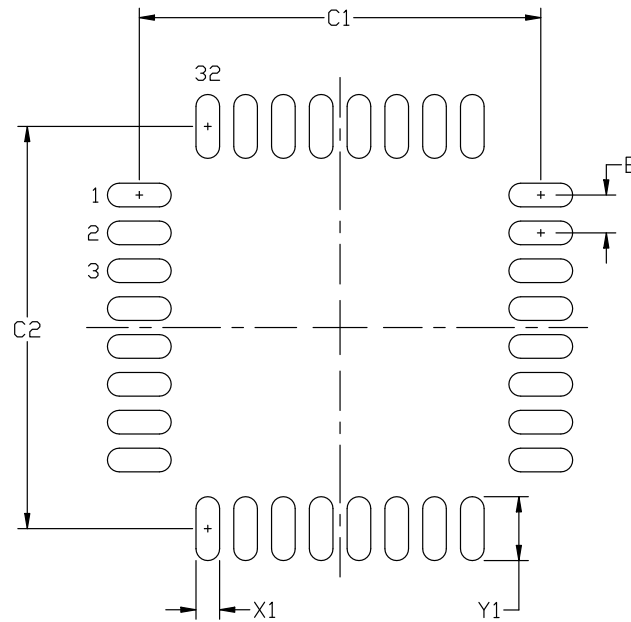
Figure 9.2. QFP32 PCB Land Pattern Drawing

Table 9.2. QFP32 PCB Land Pattern Dimensions

Dimension	Min	Max
C1	8.40	8.50
C2	8.40	8.50
E	0.80 BSC	
X1	0.40	0.50
Y1	1.25	1.35

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. This Land Pattern Design is based on the IPC-7351 guidelines.
3. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 μm minimum, all the way around the pad.
4. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.
5. The stencil thickness should be 0.125 mm (5 mils).
6. The ratio of stencil aperture to land pad size should be 1:1 for all perimeter pads.
7. A No-Clean, Type-3 solder paste is recommended.
8. The recommended card reflow profile is per the JEDEC/IPC J-STD-020C specification for Small Body Components.

9.3 QFP32 Package Marking
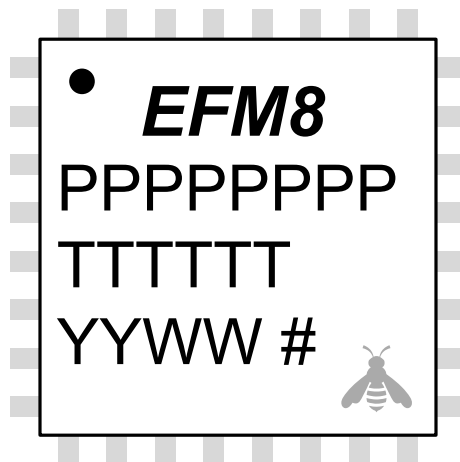
Figure 9.3. QFP32 Package Marking

The package marking consists of:

- PPPPPPPP – The part number designation.
- TTTTTT – A trace or manufacturing code.
- YY – The last 2 digits of the assembly year.
- WW – The 2-digit workweek when the device was assembled.
- # – The device revision (A, B, etc.).

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